

Teradyne Di-Series Introductions at AUTOESTCON 2008

- Eight new models of the highly successful Di-Series Digital Test Instruments satisfy a wide range of price/performance requirements
 - 32 or 64 channels per instrument
 - 25 or 50 MHz data and clock rates
 - $\pm 15V$ or $\pm 30V$ levels
- New features address emerging test requirements
 - Select models include 100 MHz data and clock rates
 - Pairing adjacent channels accommodates both 100 MHz test and differential logic
 - Example: One instrument provides 32 LVDS pairs with 100 MHz data & clock rate on each pair
 - Per-channel 8M Deep Serial Memory facilitates efficient block parallel bus transfers
 - MemTest permits RAM/ROM test enhancement of existing TPSs and ITAs because it works with arbitrary bus wiring between instrument channels and the UUT
- The Di-Series instruments provide the ultimate in legacy Teradyne compatibility
 - Superset of M9-Series, L-Series, and CASS hardware specifications with special provisions behavioral variations
 - *TPS Converter Studio* software is the proven path to transport CASS and L-Series digital tests directly to the Di-Series based on 10 years of success